Silcon Carolice (SiC) Moselli – EliteSiC, 13 mohm, 1200 V, M3S, Die NTCR013N120M3S

Description

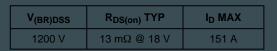
Silicon Carbide (SiC) MOSFET uses a completely new technology that provides superior switching performance and higher reliability compared to Silicon. In addition, the low ON resistance and compact chip size ensure low capacitance and gate charge. Consequently, system benefits include highest efficiency, faster operation frequency, increased power density, reduced EMI, and reduced system size.

Features

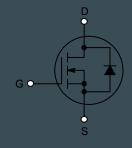
- Typ. $R_{DS(on)} = 13 \text{ m}\Omega @ V_{GS} = 18 \text{ V}$
- Low Switching Losses (Typ. E_{ON} 563 J at 75 A, 800 V)

Applications

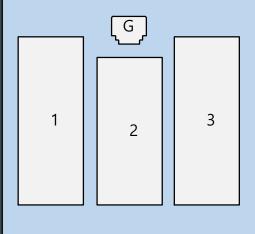
- Solar Inverters
- Electric Vehicle Charging Stations
- Uninterruptible Power Supplies (UPS)
- Energy Storage Systems
- Switch Mode Power Supplies (SMPS)



N-CHANNEL MOSFET







Die Information

- Wafer Diameter
- Die Size
- Metallization
- Тор
- Back
- Die Thickness
- Gate Pad Size

30 x	6,380	μm

Al/Si/Cu 5 μm Ti/NiV/Ag 0.5 μm

Typ. 100 μm 1300 x 1068 μm

© Semiconductor Components Industries, LLC, 2023 October, 2023 – Rev. 1

Die Layouc6.52 1 76.0002 Tc 551.622 c3906 Tm0 06.tre Di5SSoi2.6250 06.tre Di5S

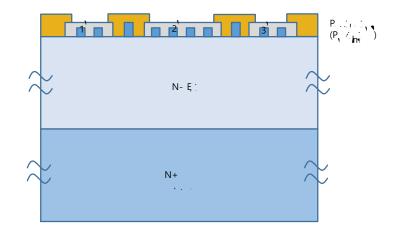


Figure 1. Bare Die Dimensions

THERMAL CHARACTERISTICS

Parameter	Symbol	Тур	Max	Unit
Junction-to-Case - Steady State (Note 4)	$R_{ ext{ heta}JC}$	0.17	0.22	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{ hetaJA}$	-	40	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
OFF-STATE CHARACTERISTICS						

••••••						
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 V, I_D = 1 mA$	1200	-	-	V
Drain-to-Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}/T_J$	I _D = 1 mA, referenced to 25°C (Note 9)		0.3		V/°C
Zero Gate Voltage Drain Current	I _{DSS}	V_{GS} = 0 V, V_{DS} = 1200 V, T_{J} = 25°C	-	-	100	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{GS} = +22/-10 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	-	-		

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified) (continued)

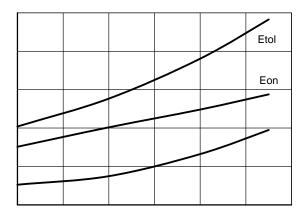
t_{RR}

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit	
SOURCE-DRAIN DIODE CHARACTERISTICS							

Reverse Recovery Time

 V_{GS} = -3/18 V, I_{SD} = 75 A, dI_S

TYPICAL CHARACTERISTICS



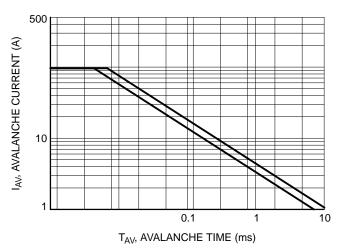


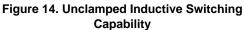
TYPICAL CHARACTERISTICS

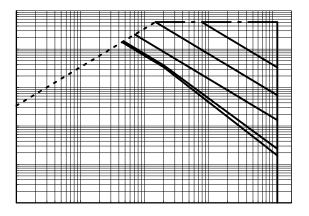
 	1	1	-	



TYPICAL CHARACTERISTICS







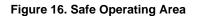


Figure 15. Maximum Continuous Drain Current vs. Case Temperature

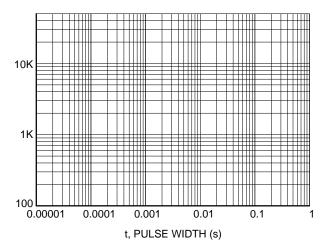


Figure 17. Single Pulse Maximum Power Dissipation

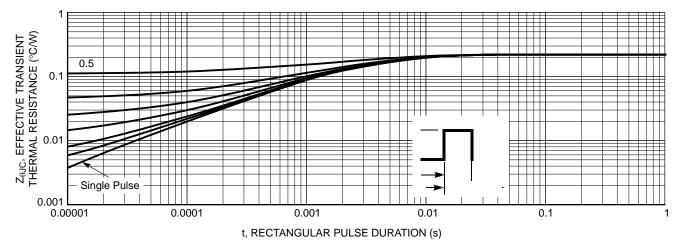


Figure 18. Junction-to-Case Transient Thermal Response

onsemi, , and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or incruit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi